L Number	Hits_	Search Text	DB	Time stamp
85	76	distance with (template and (substrate or wafer))	USPAT;	2004/04/13 14:15
			US-PGPUB;	
			EPO; JPO;	
06			DERWENT;	
			IBM_TDB	
86	550	pattern\$2 near template and (substrate or wafer)	USPAT;	2004/04/13 14:43
		,	US-PGPUB;	
			EPO; JPO;	
88			DERWENT;	
	16	(22) with (nattorned) near template and (substrate or wafer)	IBM_TDB	2004/04/12 14:44
00	10	gap with (pattern\$2 near template and (substrate or wafer))	USPAT;	2004/04/13 14:44
			US-PGPUB;	
			EPO; JPO;	
		·	DERWENT; IBM_TDB	
89	33	determin\$3 with (pattern\$2 near template and (substrate or	USPAT;	2004/04/13 14:45
	33	wafer))	US-PGPUB;	2004/04/13 14.43
		Water yy	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
90	86	(pattern\$2 near template and (substrate or wafer)) and	USPAT;	2004/04/13 14:45
		distance and gap	US-PGPUB;	200 1/0 1/15 1 11 15
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
91	18	((pattern\$2 near template and (substrate or wafer)) and	USPAT;	2004/04/13 14:45
		distance and gap) and light near reflect\$3	US-PGPUB;	. ,
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
92	84	gap with (template and (substrate or wafer))	USPAT;	2004/04/13 14:46
			US-PGPUB;	
[EPO; JPO;	
			DERWENT;	
03	0.4	21 7 17 1	IBM_TDB	
93	84	gap with (template and (substrate or wafer))	USPAT;	2004/04/13 14:46
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
87	44	(meacure 3 or determine 4) with (natterne 2 non-to	IBM_TDB	2004/04/12 14:46
07	77	(measur\$3 or determin\$4) with (pattern\$2 near template and (substrate or wafer))	USPAT;	2004/04/13 14:46
1		and (Substrate of Water))	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	